

4th Belle II PXD/SVD Workshop and 14th International Workshop on
DEPFET Detectors and Applications



Contribution ID: 87

Type: **not specified**

First Results on EMCM Testing

Tuesday 22 October 2013 13:45 (30 minutes)

Presenters: KOFFMANE, Christian; LÜTTICKE, Florian

Session Classification: PXD Testsystems